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**PATENT**  
29284/541



**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

APPLICANTS: HIROI, Takashi et al.

SERIAL NO. : Division (5) of 09/450,856

FILED : Herewith

FOR : Inspection Method, Apparatus and System for Circuit Pattern

ART UNIT : 2877 (Expected)

ASSISTANT COMMISSIONER FOR PATENTS  
Washington, D.C. 20231

**INFORMATION DISCLOSURE STATEMENT  
UNDER 37 C.F.R. § 1.97 & § 1.98**


S I R:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

Since all of the references have either been submitted or were cited by the Examiner in parent application Serial No. 09/450,856, no copies of the references are required.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,

  
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Date: April 11, 2001

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